

# Schedule of Accreditation

issued by

## United Kingdom Accreditation Service

2 Pine Trees, Chertsey Lane, Staines-upon-Thames, TW18 3HR, UK

 <p><b>UKAS</b> TESTING</p> <p><b>2806</b></p> <p>Accredited to <b>ISO/IEC 17025:2017</b></p>	<p><b>Reltech Limited</b></p> <p>Issue No: 014    Issue date: 03 July 2021</p>	
	<p>Cam Mills Lower Cam Dursley Gloucestershire GL11 5PW</p>	<p>Contact: Mr M Ashley Tel: +44 (0)1453 541200 Fax: +44 (0)1453 545810 E-Mail: sales@reltech.co.uk Website: www.reltech.co.uk</p>
<p>Testing performed at the above address only</p>		

### DETAIL OF ACCREDITATION

Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used
ELECTRICAL AND ELECTRONIC COMPONENTS, INCLUDING SOLID STATE ELECTRONIC AND SEMICONDUCTOR DEVICES	<p>ENVIRONMENTAL TESTS (Non Explosive Items)</p> <p>HIGH/LOW TEMPERATURE</p> <p>Max Temp: + 200 °C Max Chamber Size: 0.36 m x 0.8 m x 0.45 m Minimum Temp: - 40 °C Max Chamber Size: 0.46 m x 0.60 m x 0.60 m</p>	<p>JEDEC Standard Specifications</p> <p>AEC-Q100-Rev H AEC-Q100-Rev H Standard to the extent covered in the JEDEC tests below</p> <p>JESD22 - A103E:Oct 2015 High Temperature Storage (HTS) Condition A: + 125 °C Condition B: + 150 °C Condition C: + 175 °C Condition D: + 200 °C Condition G: + 85 °C JESD22-A108F:Oct 2015 Including: High Temperature Operating Life (HTOL) Low Temperature Operating Life (LTOL) High Temperature Forward Bias (HTFB) High Temperature Reverse Bias (HTRB) High Temperature Gate Bias (HTGB)</p> <p>JESD22-A119: Oct 2015 Low Temperature Storage (LTS)</p>



2806  
Accredited to  
ISO/IEC 17025:20175

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**Reltech Limited**  
Issue No: 014 Issue date: 03 July 2021

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ELECTRICAL AND ELECTRONIC COMPONENTS, INCLUDING SOLID STATE ELECTRONIC AND SEMICONDUCTOR DEVICES (cont'd)	ENVIRONMENTAL TESTS (Non Explosive Items) (cont'd)  TEMPERATURE CYCLING  Max Temp: + 150 °C Max Temp: - 65 °C Max Chamber Size: 0.32 m x 0.23 m x 0.48 m  TEMPERATURE/HUMIDITY  Temp: + 85 °C Relative Humidity: 85 % RH Max Chamber Size: 0.6 m x 0.6 m x 0.6 m  ELECTRICAL OPERATION AND MEASUREMENT  DC Voltage: 100 mV to 1000 V	JEDEC Standard Specifications  JESD22-A104F: Nov 2020 Conditions: A, B, C, G, H, I, J, K, L, M, N  JESD22-A101D.01: Jan 2021 Steady State Temperature Humidity Bias Life Test (THB)  Documented In-House Methods and Customer specified requirements
END		